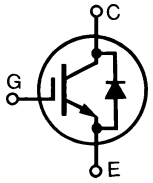
IXYS

HiPerFAST™ IGBT with Diode ISOPLUS247™

(Electrically Isolated Backside)

IXGR 32N60CD1

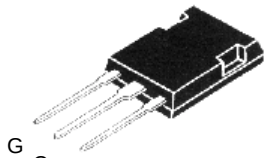
V_{CES} = 600 V
I_{C25} = 45 A
$V_{CE(SAT)typ}$ = 2.1 V
$t_{fi(typ)}$ = 55 ns



Symbol	Test Conditions	Maximum Ratings	
V_{CES}	T_J = 25°C to 150°C	600	V
V_{CGR}	T_J = 25°C to 150°C; R_{GE} = 1 MΩ	600	V
V_{GES}	Continuous	±20	V
V_{GEM}	Transient	±30	V
I_{C25}	T_C = 25°C	45	A
I_{C90}	T_C = 90°C	28	A
I_{CM}	T_C = 25°C, 1 ms	120	A
SSOA (RBSOA)	V_{GE} = 15 V, T_{VJ} = 125°C, R_G = 10 Ω Clamped inductive load, L = 100 µH	I_{CM} = 64 @ 0.8 V_{CES}	A
P_C	T_C = 25°C	140	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
Maximum Lead and Tab temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	°C
V_{ISOL}	50/60 Hz, RMS t = 1 min leads-to housing	2500	V~
Weight		5	g

ISOPLUS 247™ (IXGR)

E 153432



Isolated backside*

G = Gate, C = Collector,
E = Emitter, TAB = Collector

*Patent pending

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
BV_{CES}	I_C = 250µA, V_{GE} = 0 V	600			V
$V_{GE(th)}$	I_C = 250 µA, V_{CE} = V_{GE}	2.5		5.0	V
I_{CES}	V_{CE} = 0.8 • V_{CES} T_J = 25°C V_{GE} = 0 V T_J = 125°C			200 3	µA mA
I_{GES}	V_{CE} = 0 V, V_{GE} = ±20 V			±100	nA
$V_{CE(sat)}$	I_C = I_T, V_{GE} = 15 V Note 1		2.1	2.5	V

Features

- DCB Isolated mounting tab
- Meets TO-247AD package Outline
- High current handling capability
- Latest generation HDMOS™ process
- MOS Gate turn-on
  - drive simplicity

Applications

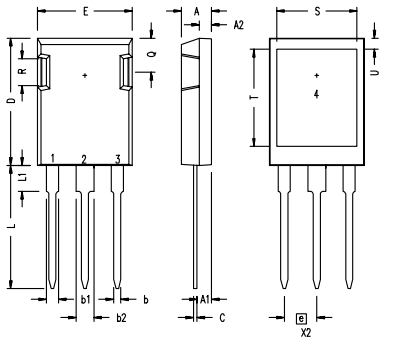
- Uninterruptible power supplies (UPS)
- Switched-mode and resonant-mode power supplies
- AC motor speed control
- DC servo and robot drives
- DC choppers

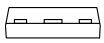
Advantages

- Easy assembly
- High power density
- Very fast switching speeds for high frequency applications

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
g_{fs}	$I_C = I_T$; V_{CE} = 10 V, Pulse test, t ≤ 300 µs, duty cycle ≤ 2 %		25		S
C_{ies}	V_{CE} = 25 V, V_{GE} = 0 V, f = 1 MHz		2700		pF
C_{oes}			240		pF
C_{res}			50		pF
Q_g	$I_C = I_T$, V_{GE} = 15 V, V_{CE} = 0.5 V_{CES}		110		nC
Q_{ge}			22		nC
Q_{gc}			40		nC
$t_{d(on)}$	**Inductive load, T_J = 25°C**		25		ns
t_{ri}	$I_C = I_T$, V_{GE} = 15 V, L = 100 µH,		20		ns
$t_{d(off)}$	V_{CE} = 0.8 V_{CES}, $R_G = R_{off}$ = 4.7 Ω		85		ns
t_{fi}	Remarks: Switching times may increase for V_{CE} (Clamp) > 0.8 • V_{CES},		55		ns
E_{off}	higher T_J or increased R_G		0.32		mJ
$t_{d(on)}$	**Inductive load, T_J = 125°C**		25		ns
t_{ri}	$I_C = I_T$, V_{GE} = 15 V, L = 100 µH		25		ns
E_{on}	V_{CE} = 0.8 V_{CES}, $R_G = R_{off}$ = 4.7 Ω		1		mJ
$t_{d(off)}$	Remarks: Switching times may		110	170	ns
t_{fi}	increase for V_{CE} (Clamp) > 0.8 • V_{CES},		100	160	ns
E_{off}	higher T_J or increased R_G		0.85	1.25	mJ
R_{thJC}				0.90	K/W
R_{thCK}			0.15		K/W

ISOPLUS 247 (IXGR) OUTLINE





1 Gate, 2 Drain (Collector)
3 Source (Emitter)
4 no connection

Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.83	5.21	.190	.205
A_1	2.29	2.54	.090	.100
A_2	1.91	2.16	.075	.085
b	1.14	1.40	.045	.055
b_1	1.91	2.13	.075	.084
b_2	2.92	3.12	.115	.123
C	0.61	0.80	.024	.031
D	20.80	21.34	.819	.840
E	15.75	16.13	.620	.635
e	5.45 BSC		.215 BSC	
L	19.81	20.32	.780	.800
L1	3.81	4.32	.150	.170
Q	5.59	6.20	.220	.244
R	4.32	4.83	.170	.190
S	13.21	13.72	.520	.540
T	15.75	16.26	.620	.640
U	1.65	3.03	.065	.080

Reverse Diode (FRED)

Symbol	Test Conditions	Characteristic Values (T_J = 25°C, unless otherwise specified) min.	typ.	max.	
V_F	$I_F = I_T$, V_{GE} = 0 V, Pulse test	T_J = 150°C		1.6	V
	t ≤ 300 µs, duty cycle d ≤ 2 %	T_J = 25°C		2.5	V
I_{RM}	$I_F = I_T$, V_{GE} = 0 V, $-di_F/dt$ = 100 A/µs		6		A
t_{rr}	V_R = 100 V	T_J = 100°C	100		ns
	I_F = 1 A; -di/dt = 100 A/µs; V_R = 30 V	T_J = 25°C	25		ns
R_{thJC}				1.15	K/W

Note: 1. I_T = 32A

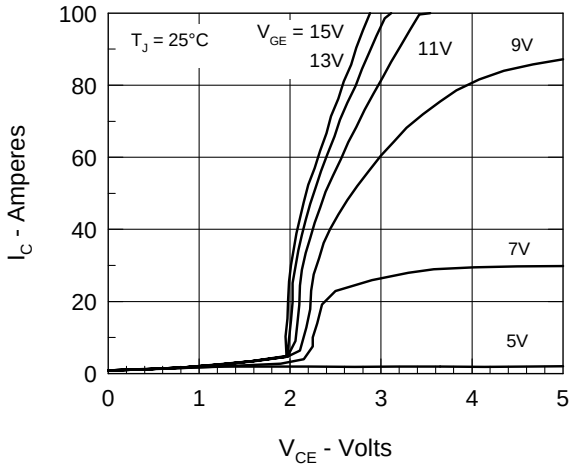


Fig. 1. Output Characteristics

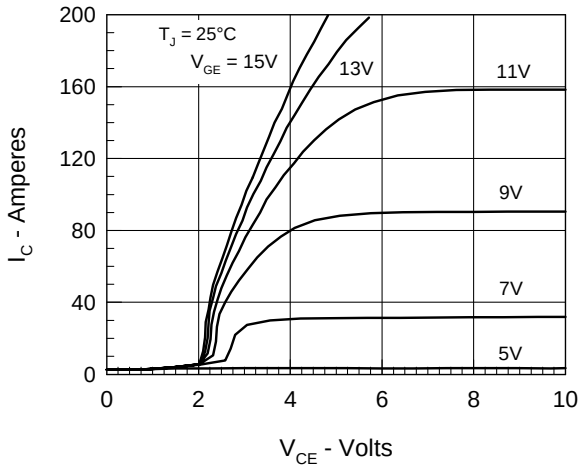


Fig. 2. Extended Output Characteristics

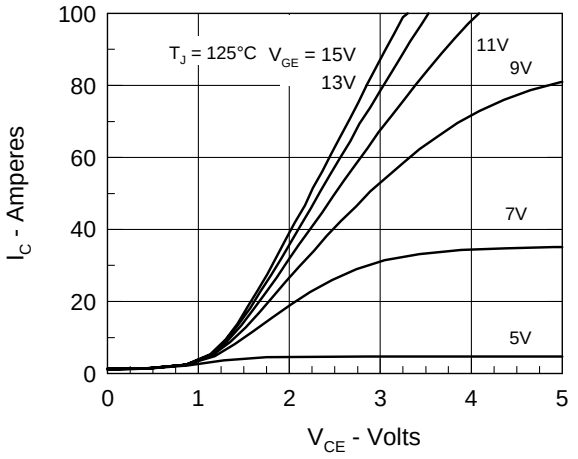


Fig. 3. High Temperature Output Characteristics

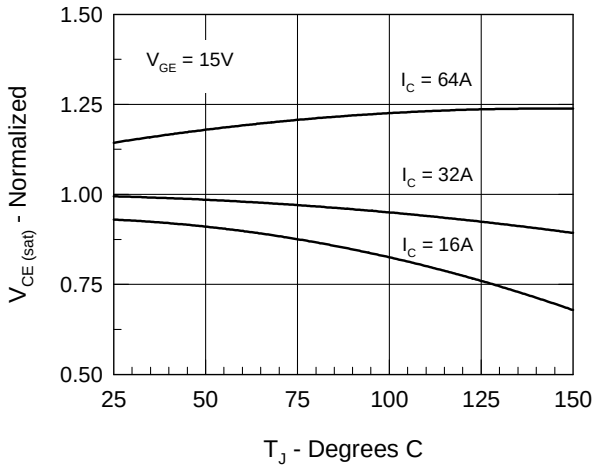


Fig. 4. Temperature Dependence of $V_{CE(sat)}$

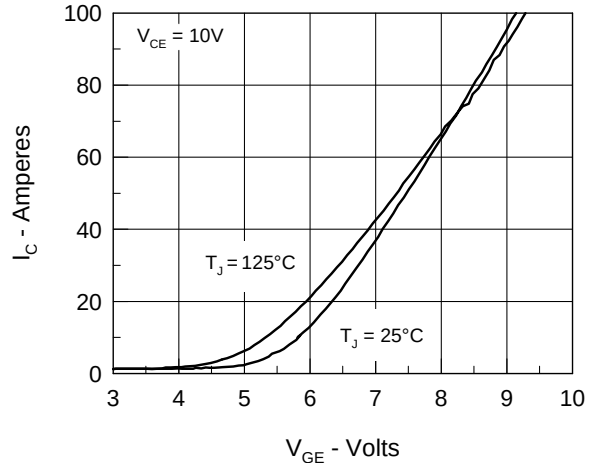


Fig. 5. Admittance Curves

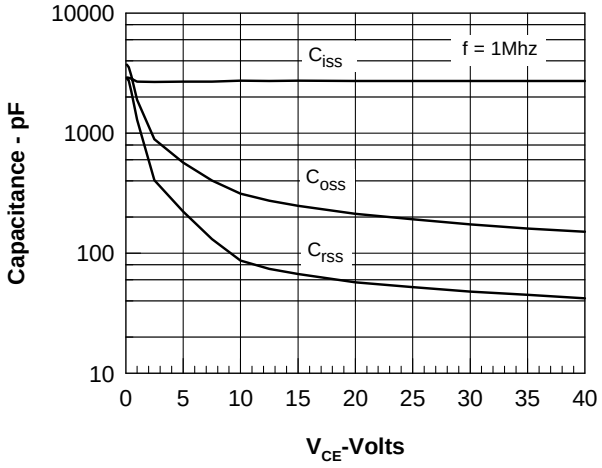


Fig. 6. Capacitance Curves

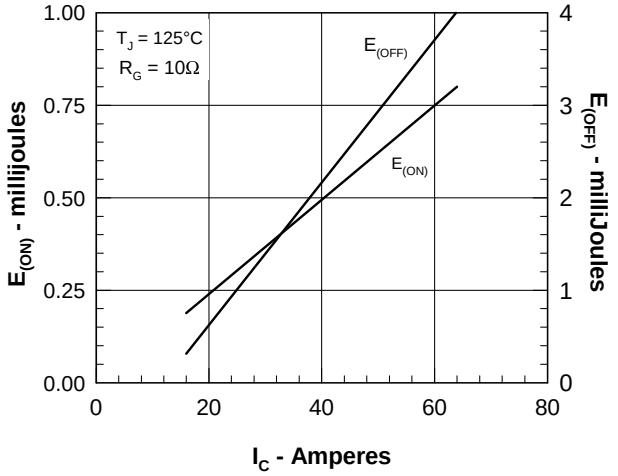


Fig. 7. Dependence of E_{ON} and E_{OFF} on I_C.

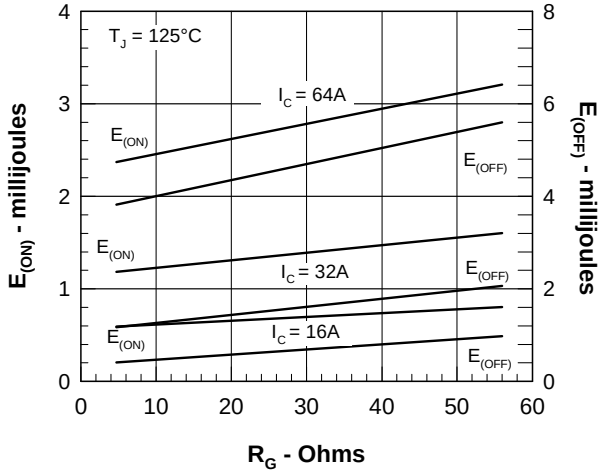


Fig. 8. Dependence of E_{ON} and E_{OFF} on R_G.

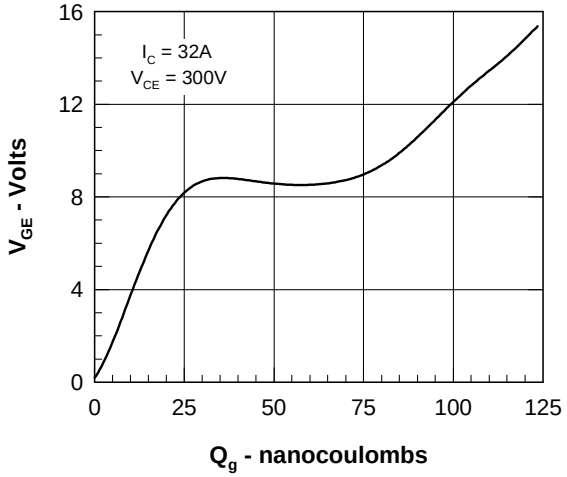


Fig. 9. Gate Charge

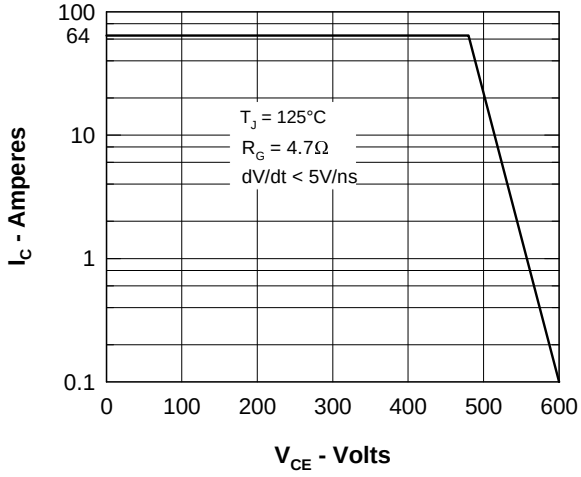


Fig. 10. Turn-off Safe Operating Area

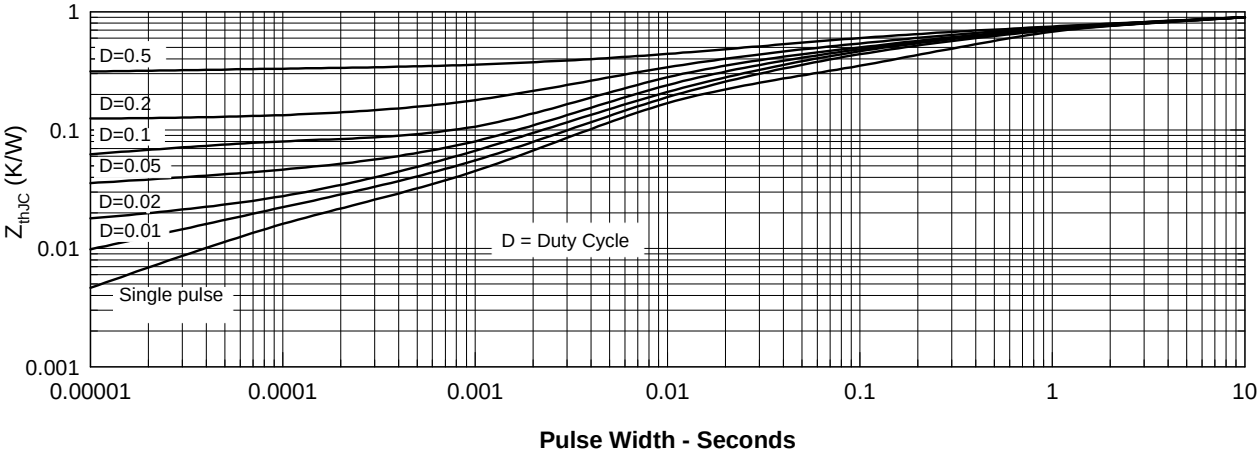


Fig. 11. Transient Thermal Resistance

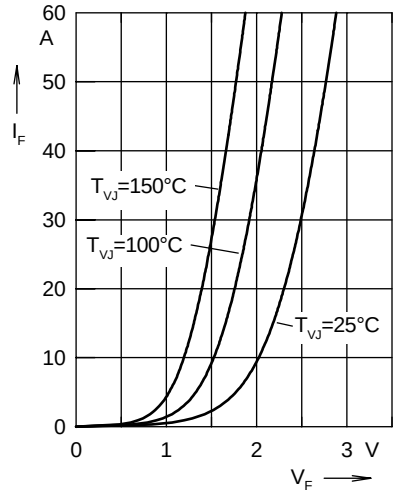


Fig. 12. Forward current I_F versus V_F

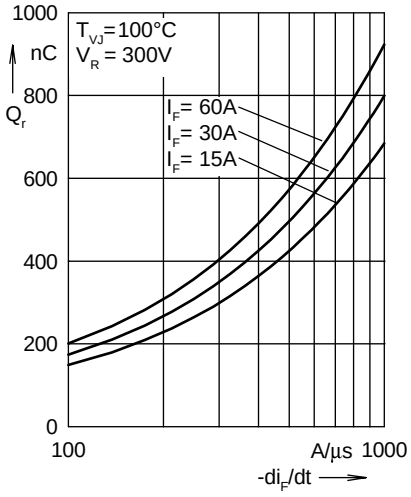


Fig. 13. Reverse recovery charge Q_r versus $-di_F/dt$

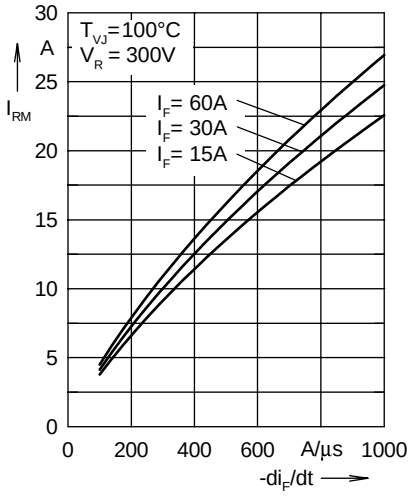


Fig. 14.Peak reverse current I_{RM} versus $-di_F/dt$

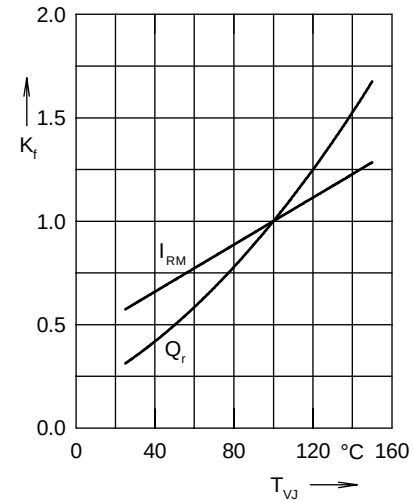


Fig. 15. Dynamic parameters Q_r, I_{RM} versus T_{VJ}

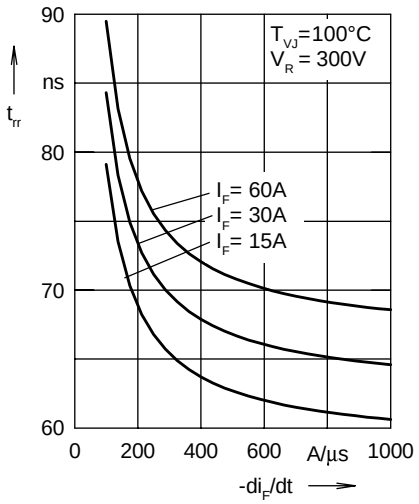


Fig. 16.Recovery time t_{rr} versus $-di_F/dt$

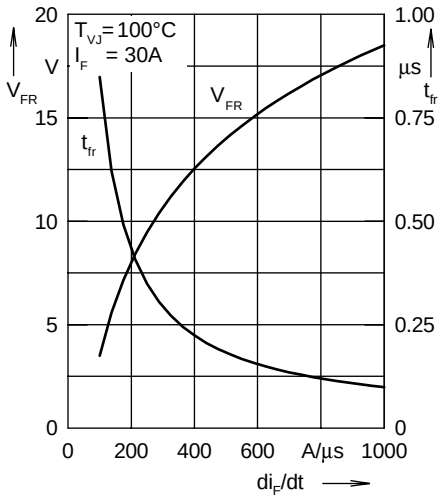


Fig. 17.Peak forward voltage V_{FR} and t_{fr} versus di_F/dt

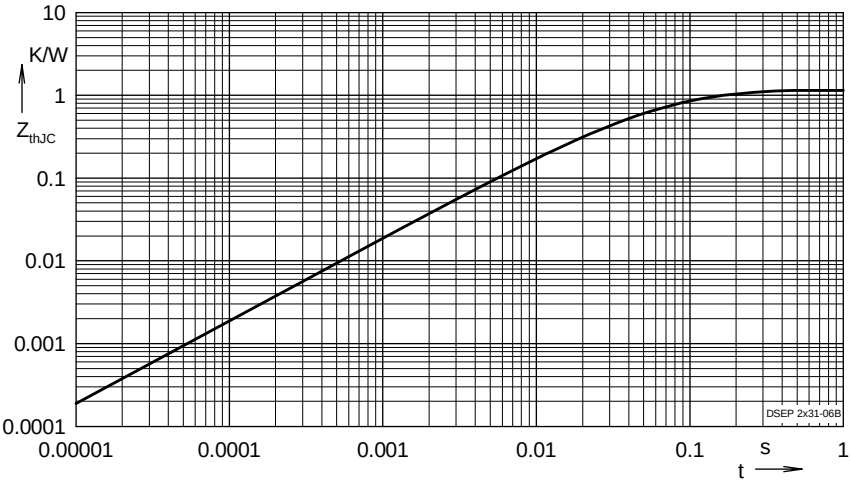


Fig. 18. Transient thermal resistance junction to case

Constants for Z_{thJC} calculation:

i	R_{thi} (K/W)	t_i (s)
1	0.436	0.0055
2	0.482	0.0092
3	0.117	0.0007
4	0.115	0.0418